

Supplementary material

On the use of oxidation induction time as a kinetic parameter for condition monitoring and lifetime evaluation under ionizing radiation environments

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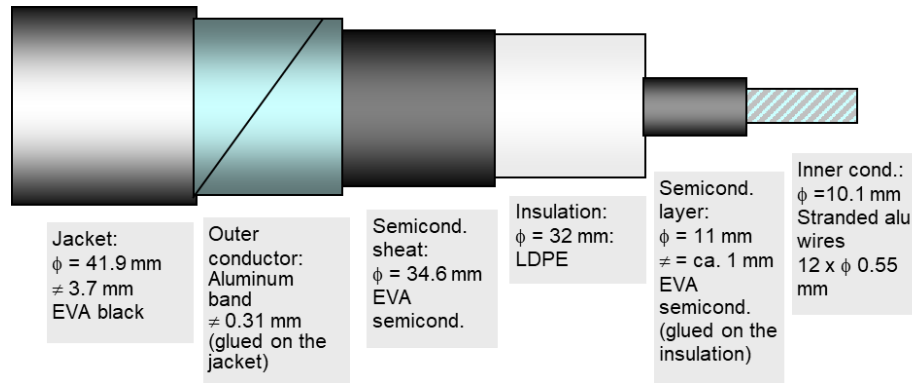


Figure S1. Structure of C1 cable [General purpose, High Voltage - HV- coaxial cable]

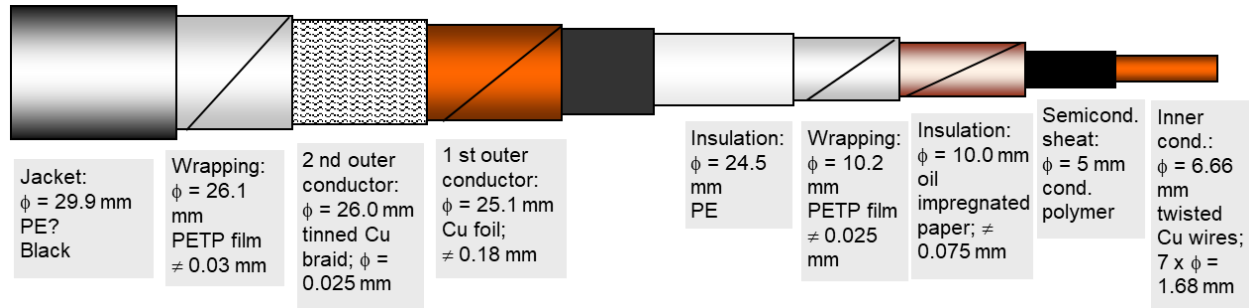


Figure S2. Structure of C4 cable (General purpose, HV/HF coaxial cable)

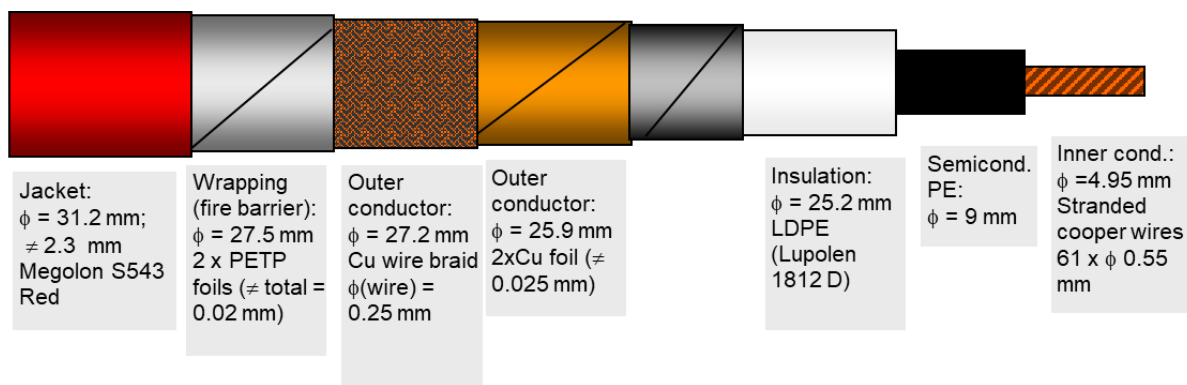


Figure S3. Structure of C3 cable (General purpose, HV/HF - High Frequencies - coaxial cable)

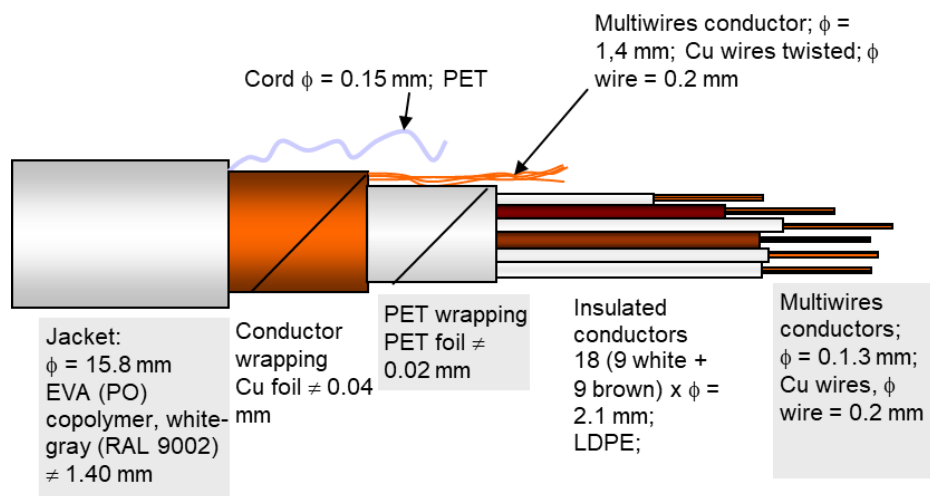


Figure S4. Structure of C9 cable (General purpose, I&C - Instrumentation and Control- cable)

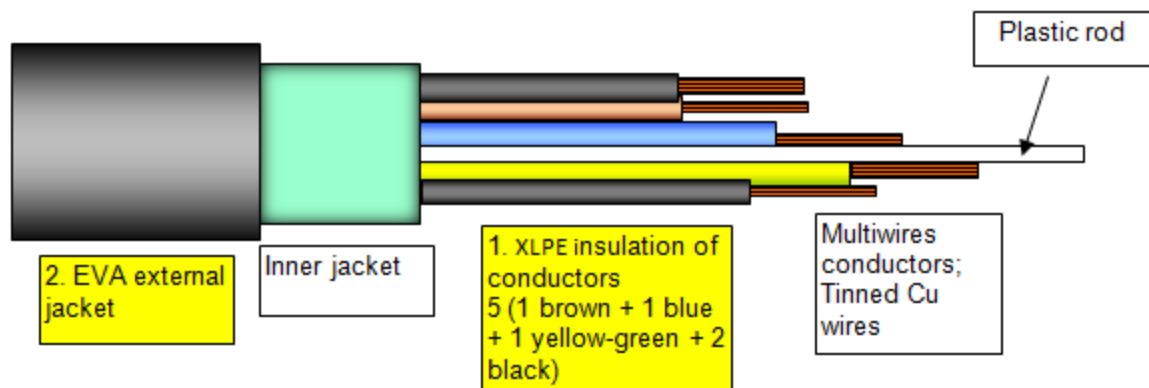


Figure S5. Structure of IC1 cable (General purpose, I&C - Instrumentation and Control- cable)

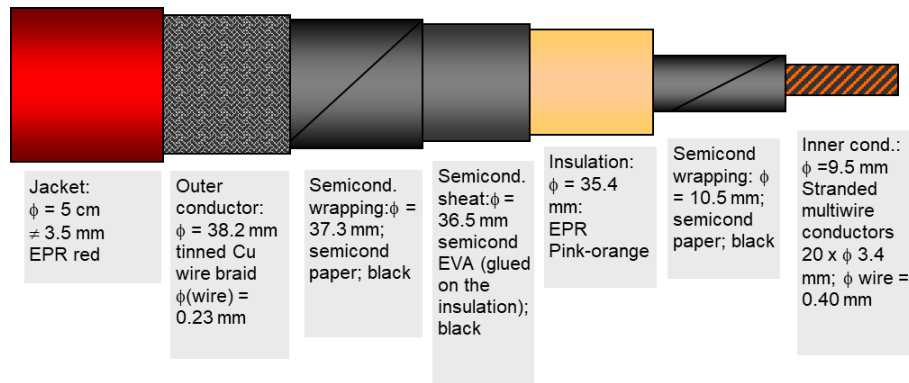


Figure S6. Structure of C2 cable (General purpose, HV, coaxial cable)

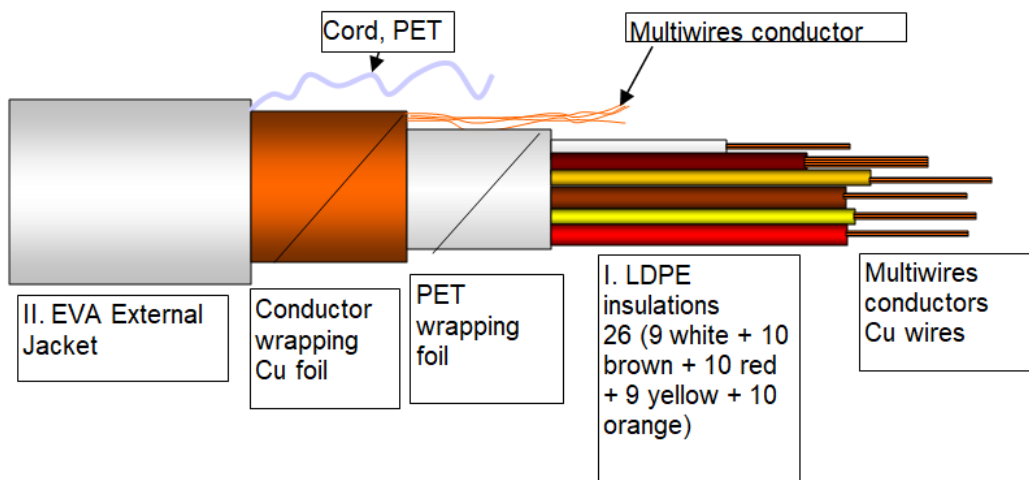


Figure S7. Structure of IC2 cable (General purpose, I&C - Instrumentation and Control- cable)